



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re the Application of:

CHEN, KAI et al.

Group Art Unit: **2877**

Serial No.: **10/002,000**

Examiner: **Vincent P. BARTH**

Filed: **December 5, 2001**

P.T.O. Confirmation No.: **2814**

**FOR: AXIS DETERMINATION APPARATUS,
FILM-THICKNESS MEASUREMENT APPARATUS,
DEPOSITION APPARATUS, AXIS DETERMINATION
METHOD, AND FILM-THICKNESS MEASUREMENT METHOD**

AMENDMENT UNDER 37 CFR §1.111

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

November 25, 2003

Sir:

In response to the Office Action dated **August 29, 2003**, please amend the above-identified application as follows:

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DEC - 1 2003
PTC 2800 MAIL ROOM